

- infinitely sharp band-pass filter, 346
 information content, 339, 341
 information loss, 322, 513
 information redundancy, 259
 initial condition, 518
 initial state, 223
 initialization, 212
 initialization fault, 62, 70, 217
 initialization phase, 240
 initialization vectors, 239
 INL, 326, 364
 inout pin, 571
 INPUT cell, 571
 input leakage, 302
 input MUX, 494, 496, 512, 526
 instruction fault, 62, 597
 instruction register, 553, 571
 instruction register OPCODE, 571
 instructions of SOCRATES, 198
 integer-ratio synchronization, 319
 integral linearity error function, 326
 integral non-linearity, 326
 integral non-linearity error, 364
 integrated services data network, 540
 integration interval, 337
 intellectual property, 606
 inter-gate bridge, 447
 interconnect analog test, 586
 interconnect bridging, 441
 interconnect test, 591
 interdiffusion, 260
 intermittent fault, 62, 65, 259
 intermodulation component, 356
 intermodulation distortion, 315, 323, 356, 359
 intermodulation distortion test, 374
 intermodulation product, 349, 361
 INTERNAL cell, 571
 internal exclusive-OR LFSR, 507
 internal memory state, 212
 International Telegraph and Telephone Consultative Committee, 359
 interrupt test, 305
 interval counter, 380
 INTTEST instruction, 560, 588, 589
 intra-gate bridge, 447
 intrinsic error, 370
 intrinsic parameter, 315, 323
 inversion coupling fault, 258, 269
 inverted signal flow graph, 407, 412
 invertible function, 513
 ionic contamination, 261
 IP, 606
 IP core, 606
 irreducible polynomial, 495, 616
 irreducible tones, 356
 irredundant test, 263
 ISDN, 540
 isolation transistor, 585
 Iyengar, V., 627
 Iyengar, V. S., 61
 Jacobian matrix, 393
 Jain, 131, 534
 Jalote, 625
 JEDEC, 562
 Jha, 69, 148, 621, 625
 jitter, 315
 jitter noise, 376
 jitter testing, 299
 jitter-induced sampling error, 358
 Johnson, 625
 Johnson counter pattern generator, 543
 Joint Electron Device Engineering Council, 562
 Joint Test Action Group, 549
 JTAG, 549
 JTAG bi-directional pin, 565
 JTAG boundary scan, 496
 k-coupling fault, 269, 272
 Kaminska, 206, 398, 402, 622
 Khare, 627
 Kime, 602, 610
 Kinoshita, 239, 536, 537
 KMS algorithm, 437
 Kohavi, 621
 Koren, 625
 Krstić, 624
 ks/s, 315
 Kundu, 625
 Kunz, 200, 626
 Kurshan, 626
 Lala, 625
 latch-up, 459
 lattice, 261
 law of diminishing returns, 40
 layout optimization, 434
 leaf-macro, 610
 leakage, 591
 leakage current, 302
 leakage fault, 444, 446, 448
 leakage fault table, 450
 leakage test, 302
 learning procedure, 197
 Lee, C. Y., 158
 Lee, M. T. C., 626
 legacy core, 606
 level numbering, 180
 level order, 132, 135
 level ordering algorithm, 136
 level-sensitive scan design, 50, 468, 477, 524
 levelization, 102
 levelization procedure, 226
 Levi, 439
 LFSR, 300, 495, 498, 503
 LFSR cycle length, 505
 LFSR up/down counter, 531, 534
 LFSR with all-zero pattern, 530
 lightening arrester, 15
 Lin, 391, 422